

METHODS OF DETERMINING A QUALITY OF AN ARRAY SUBSTRATE

ABSTRACT OF THE DISCLOSURE

[00136] Methods and devices for determining a quality of a substrate surface are provided. Embodiments of the subject methods include producing a plurality of droplets on the surface of a substrate, illuminating the droplet-coated surface, observing a resultant optical property from the surface; and evaluating a quality of the substrate based on the observed optical property. In certain embodiments, an evaluated substrate is one which is to be used in the fabrication of an array assembly and the evaluation is performed prior to fabricating an array on the subject surface. In certain embodiments, an evaluated substrate is one which includes one or more arrays thereon and the evaluation is performed subsequent to the fabrication of the array on the substrate, e.g., to evaluate the quality of the features of the fabricated array. Also provided are apparatuses, systems and kits for use in practicing the subject methods.